


<b>Search Notes</b>  	<b>Application/Control No.</b>  10540670	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG, CHIN
	<b>Examiner</b>  Rainey, Robert R	<b>Art Unit</b>  2629

SEARCHED			
Class	Subclass	Date	Examiner
340	815.45	12/12/2007	RR
345	691	12/12/2007	RR

SEARCH NOTES		
Search Notes	Date	Examiner
PLUS	11/01/2007	RR
QEM	11/06/2007	RR
QEM	12/12/2007	RR
EAST Search	12/12/2007	RR
Inventor Name Search PALM	12/12/2007	RR
EAST Search	11/13/2008	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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